NSN 6625-01-433-4400

Semiconductor Device Test Set - Page 1 of 1

View Online at https://aerobasegroup.com/nsn/6625-01-433-4400

Inclosure Feature:

Single item w/housing

Test Type For Which Designed:

Parametric characterization of semiconductors

Special Features:

3.5 inch ms-dos compatible disk storage; 16v, 80v, 400v, 2000v ranges

Shelf Life:

N/a

Unit Of Measure:

--

Demilitarization:

Yes - demil/mli

Fiig:

T228-a